
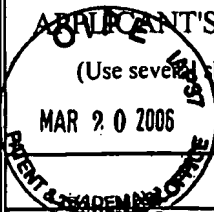
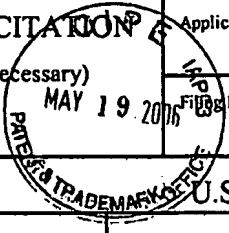


<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)		Application		OFGS File No. <b>P/2635-72</b>			
		Applicant <b>Toru NAKAZAWA</b>					
		Filing Date		Group Art Unit			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
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	US-						
<b>FOREIGN PATENT DOCUMENTS</b>							
/PT/ 	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	2002-330168	11/2002	Japan			No	
	8-8995	01/1996	Japan			No	
	2002-135277	05/2002	Japan			No	
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	2002-281106	09/2002	Japan			No	
	2001-160842	06/2001	Japan			No	
	6-252978	09/1994	Japan			No	
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
Examiner	/Phuc Tran/		Date Considered <b>09/17/2007</b>				
<small>EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.</small>							

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary) <b>MAR 20 2006</b> 		Application <b>10/780,957</b>		OFGS File No. <b>P/2635-72</b>		
		Applicant <b>Toru NAKAZAWA</b>				
		Filing Date <b>February 18, 2004</b>		Group Art Unit <b>2661</b>		
<b>U.S. PATENT DOCUMENTS</b>						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
/PT/	US-2001/0015956 A1	08-2001	Ono			
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	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
<b>FOREIGN PATENT DOCUMENTS</b>						
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation
						Yes No
/PT/	WO 01/93513 A2	12-2001	PCT			X
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
/PT/		List of Prior Ars for Information Disclosure Statement prepared by applicant in connection				
/PT/		with the instant application				
/PT/		Office Action issued by Chinese Patent Office on January 27, 2006 in connection with				
/PT/		corresponding Chinese application no. 200410005801.3				
/PT/		English translation of Chinese Office Action dated January 27, 2006 issued in				
/PT/		connection with corresponding Chinese applicatin no. 200410005801.3				
Examiner <b>/Phuc Tran/</b>		Date Considered <b>09/17/2007</b>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)		Application 10/780,957		OFGS File No. P/2635-72			
		Applicant Toru NAKAZAWA					
		Filing Date February 18, 2004		Group Art Unit 2661			
		<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
	US-						
<b>FOREIGN PATENT DOCUMENTS</b>							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
/PT/	2003-0008324	01-2003	Korea				X
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
/PT/		List of Prior Arts for Information Disclosure Statement prepared by Korean associate					
		<i>Bounds on the Throughput Performance of ARQ Selective-Repeat Protocol in Markov</i>					
		<i>Channels, M. Zorzi, et. al., ICC 96, Vol. 2, pp. 782-786</i>					
		Office Action issued by Korean Patent Office on January 31, 2006 in connection with					
		corresponding Korean application no. 10-2004-0010692					
		Japanese translation of Korean Office Action dated January 31, 2006					
		issued in connection with corresponding Korean application no. 10-2004-0010692					
↓		English translation of Japanese translation of Korean Office Action dated January 31, 2006					
/PT/		issued in connection with corresponding Korean application no. 10-2004-0010692					
Examiner /Phuc Tran/		Date Considered 09/17/2007					
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